

# Author Index

## A

Ahn, SJ, 112  
Ang, WK, 106  
Arai, F, 84

## B

Berdnikov, AS, 78, 170  
Berg, GPA, 160  
Berz, M, 2, 8, 14, 20, 36, 224

## C

Cheong, KH, 142  
Cho, B, 112

## D

Danilatos, GD, 194  
De Castro, O, 94  
Della Negra, S, 94  
Dickel, T, 160  
Dimitriou, A, 148  
Dowsett, D, 94, 218  
Duxbury, P, 224

## E

El Ghazaly, MOA, 44

## F

Fernández-Martín, M, 148  
Franczak, B, 160  
Frank, L, 124

## G

Geissel, H, 160  
Greenzweig, Y, 90  
Grinfeld, D, 176  
Gurov, V, 258

## H

Haettner, E, 160  
Hammer, J, 50  
Han, W, 142  
Hidaka, K, 54  
Hipple, R, 2  
Hommelhoff, P, 50  
Horák, M, 242  
Hrnčíř, T, 206  
Hudec, J, 264

## I

Ibrayev, AT, 270  
Ito, Y, 84  
Ivanov, V, 236  
Iwasa, N, 160

## J

Jagasia, R, 14  
Jiruše, J, 206

## K

Kanellakopoulos, A, 148  
Khursheed, A, 106, 130, 136, 142  
Knápek, A, 60  
Kohashi, T, 200  
Kolařík, V, 230  
Kološová, J, 206  
Konvalina, I, 66, 264  
Krátký, S, 60, 230  
Kunz, J, 20  
Kunz, J, 8

## L

Lehrach, A, 24  
Lencová, B, 188  
Loseth, B, 14, 20

## M

Madesis, I, 148  
Makarov, A, 176  
Makino, K, 8, 36, 224  
Malamud, Z, 90  
Marianowski, K, 100  
Martínez, G, 148  
Mertzimekis, TJ, 148  
Mika, F, 66, 124  
Monastyrskiy, M, 176  
Morishita, H, 200  
Müllerová, I, 66, 124  
Münzenberg, G, 160

## N

Neděla, V, 194, 264  
Nelliyan, K, 142

## O

Ogawa, T, 112  
Onuki, J, 54  
Oral, M, 194, 246, 264  
Ose, Y, 200

## P

Plaß, WR, 160  
Plies, E, 100  
Portman, J, 224  
Potapkin, OD, 252

## R

Radlička, T, 60, 212, 246  
Raveh, A, 90  
Read, FH, 182, 276  
Rosenthal, M, 30  
Ruan, CY, 224  
Rudolf, M, 206

## S

Sasaki, T, 54  
Sato, H, 200  
Sato, M, 54  
Scheidenberger, Ch, 160  
Schönhense, G, 118  
Schury, P, 84  
Sise, O, 72  
Snopok, P, 8, 20  
Solovyev, KV, 170  
Srinivasan, A, 136

## T

Tao, Z, 224  
Thomas, S, 50  
Trubitsyn, A, 258

## U

Urbánek, M, 230

## W

Wada, M, 84  
Walker, CGH, 66  
Weber, P, 50  
Weick, H, 160  
Winfield, JS, 160  
Winkler, M, 160  
Wirtz, T, 94  
Wollnik, H, 84, 154

## Y

Yavor, M, 160

## Z

Zelinka, J, 246  
Zhang, H, 20, 224  
Zlámal, J, 188, 206, 242  
Zouros, TJM, 148

## List of Participants

Adamec Pavel	ICT GmbH, Heimstetten, Germany pavel_adamec@amat.com	Grinfeld Dmitry	Thermo Fisher Scientific, Bremen, Germany dmitry.grinfeld@thermofisher.com
Andrzejewski Roch	CRP Gabriel Lippmann, Belvaux, Luxembourg andrzej@lippmann.lu	Guna Michael	AB Sciex, Concord, Ontario, Canada michael.guna@absciex.com
Ang Wei Kean	National University of Singapore, Singapore eleawk@nus.edu.sg	Gurov Victor	Ryazan State Radio Engineering University, Ryazan, Russia gurovvs@mail.ru
Averin Igor	Institute for Analytical Instrumentation RAS, St.Petersburg, Russia agreer@bk.ru	Hammer Jakob	Friedrich-Alexander Universität, Erlangen, Germany jakob.hammer@fau.de
Baisanov Orda	Military Institute of Air Defence Forces, Aktobe, Kazakhstan baisanov@mail.ru	Hipple Robert	Michigan State University, East Lansing, MI, USA hipple@msu.edu
Berdnikov Alexander	Institute for Analytical Instrumentation RAS, St.Petersburg, Russia asberd.spb@gmail.com	Hrnčír Tomáš	Tescan, Ltd., Brno, Czech Republic tomas.hrncir@tescan.cz
Berz Martin	Michigan State University, East Lansing, MI, USA berz@msu.edu	Huang Jason	Carl Zeiss Microscopy, Peabody, MA, USA jason.huang@zeiss.com
Bimurzaev Seitkerim	Almaty University of Power Engineering and Telecommunication, Almaty, Kazakhstan bimurzaev@mail.ru	Hung Quang Hoang	CRP Gabriel Lippmann, Belvaux, Luxembourg hoang@lippmann.lu
Blackburn Arthur	Hitachi Cambridge Laboratory, Cavendish Laboratory, Cambridge, UK arthur.blackburn@hitachi-eu.com	Hwang Ing-Shouh	Institute of Physics, Nankang, Taipei, Taiwan ishwang@phys.sinica.edu.tw
Cook Ben	ICT GmbH, Heimstetten, Germany benjamin_cook@amat.com	Chang Wei-Yu	National Tsing Hua University, Hsinchu, Taiwan weiyu429@gmail.com
De Castro Olivier	CRP Gabriel Lippmann, Belvaux, Luxembourg decastro@lippmann.lu	Cheong Kang Hao	National University of Singapore, Singapore g0800484@nus.edu.sg
Dellby Niklas	Nion, Kirkland, WA, USA dellby@nion.com	Ibrayev Alpamys	Almaty University of Power Engineering and Telecommunications, Almaty, Kazakhstan pok_rk@mail.ru
Dohi Hideto	Hitachi, Ibaraki, Japan dohi-hideto@naka.hitachi-hitec.com	Jagasia Ravi	Michigan State University, East Lansing, MI, USA jagasiar@msu.edu
Dowsett David	CRP Gabriel Lippmann, Belvaux, Luxembourg dowsett@lippmann.lu	Janzen Roland	Johannes Gutenberg University, Mainz, Germany info@dr-janzen.de
Dubkov Michael	Ryazan State Radio Engineering University, Ryazan, Russia dubkov.m.v@rsreu.ru	Jiang Xinrong	KLA-Tencor Co., Milpitas, CA, USA xinrong.jiang@kla-tencor.com
El Ghazaly Mohamed	King Abdulaziz City for Science and Technology (KACST), Riyadh, Saudi Arabia maelghazaly@kacst.edu.sa	Jiruše Jaroslav	Tescan, Ltd., Brno, Czech Republic jaroslav.jiruse@tescan.cz
Essers Erik	Carl Zeiss Microscopy, Oberkochen, Germany erik.essers@zeiss.com	Katsap Victor	NuFlare Technology USA, NY, USA katsap@nuflare.com
Frank Luděk	Institute of Scientific Instruments, Brno, Czech Republic ludek@isibrno.cz	Khursheed Anjam	National University of Singapore, Singapore eleka@nus.edu.sg
Gamm Bjoern	Carl Zeiss Microscopy, Oberkochen, Germany bjoern.gamm@zeiss.com	Kim Jang Youl	Institute for Basic Science, Daejeon, Korea jykim0929@ibs.re.kr
Geissel Hans	GSI Helmholtz Centre, Darmstadt, Germany geissel@gsi.de	Knápek Alexandr	Institute of Scientific Instruments, Brno, Czech Republic knappek@isibrno.cz
Greenzweig Yuval	Intel Israel, Haifa, Israel yuval.greenzweig@intel.com	Kolařík Vladimír	Institute of Scientific Instruments, Brno, Czech Republic kolariq@isibrno.cz

Konvalina Ivo Institute of Scientific Instruments, Brno, Czech Republic  
konvalina@isibrno.cz

Kovtoun Viatcheslav ThermoFisher Scientific, San Jose, CA, USA  
viatcheslav.kovtoun@thermofisher.com

Krivanek Ondrej Nion Co., Kirkland, WA, USA  
krivanek@nion.com

Kruit Pieter Delft University of Technology, Delft, Netherlands  
P.Kruit@tudelft.nl

Kunz Josiah Illinois Institute of Technology, Chicago, IL, USA  
jkunz@hawk.iit.edu

Langbrandtner Conradin Vistec Electron Beam GmbH, Jena, Germany  
Conradin.Langbrandtner@vistec-semi.com

Lehrach Andreas Forschungszentrum Jülich, Jülich, Germany  
a.lehrach@fz-juelich.de

Lencová Bohumila Tescan, Ltd., Brno, Czech Republic  
bohumila.lencova@tescan.cz

Lin Chun-Yueh Institute of Physics, Nankang, Taipei, Taiwan  
cylin@phys.sinica.edu.tw

Liska Ivo Applied Materials, Heimstetten, Germany  
ivo\_liska@amat.com

Loseth Benjamin Michigan State University, East Lansing, MI, USA  
ben.loseth@gmail.com

Maazouz Mostafa FEI Company, Hillsboro, OR, USA  
mmaazouz@fei.com

Maehl Sven SPECS Surface Nano Analysis, Berlin, Germany  
reise@specs.com

Makino Kyoko Michigan State University, East Lansing, MI, USA  
makino@msu.edu

Malinský Miloš FEI Czech Republic, Brno, Czech Republic  
milos.malinsky@fei.com

Mankos Marian Electron Optica, Palo Alto, CA, USA  
marian@electronoptica.com

Marianowski Karin University of Tübingen, Tübingen, Germany  
karin.marianowski@uni-tuebingen.de

Matsuda Kenji University of Toyama, Toyama, Japan  
matsuda@eng.u-toyama.ac.jp

Mika Filip Institute of Scientific Instruments, Brno, Czech Republic  
filip.mika@isibrno.cz

Mimura Ryo Raith GmbH, Dortmund, Germany  
mimura@raith.de

Miyamoto Nobuo NuFlare Technology, Yokohama, Japan  
miyamoto.nobuo@nuflare.co.jp

Müller Heiko CEOS GmbH, Heidelberg, Germany  
mueller@ceos-gmbh.de

Müllerová Ilona Institute of Scientific Instruments, Brno, Czech Republic  
ilona@isibrno.cz

Munro Eric Munro's Electron Beam Software, London, UK  
eric@mebs.co.uk

Murata Hidekazu Meijo University, Nagoya, Japan  
hkmurata@meijo-u.ac.jp

Nakashima Takuya Meijo University, Nagoya, Japan  
143433019@ccalumni.meijo-u.ac.jp

Ogawa Takashi Korea Reserch Institute of Standards and Science, Daejeon, Korea  
togawa@kriss.re.kr

Oral Martin Institute of Scientific Instruments, Brno, Czech Republic  
oral@isibrno.cz

Ose Yoichi Hitachi High-Technologies, Ibaraki, Japan  
ose-yoichi@naka.hitachi-hitec.com

Plies Erich University of Tübingen, Tübingen, Germany  
erich.plies@uni-tuebingen.de

Portman Jenni Michigan State University, East Lansing, MI, USA  
portman1@msu.edu

Potapkin Oleg Moscow Institute of Radio Engineering Electronics and Automation, Moscow, Russia  
potapkinod@mail.ru

Radlička Tomáš Institute of Scientific Instruments, Brno, Czech Republic  
radlicka@isibrno.cz

Read Frank CPO Ltd, Macclesfield, UK  
electronoptics@aol.com

Rose Harald University of Ulm, Ulm, Germany  
harald.rose@uni-ulm.de

Rosenthal Marcel Forschungszentrum Jülich, Jülich, Germany  
m.rosenthal@fz-juelich.de

Ruan Chong-Yu Michigan State University, East Lansing, MI, USA  
ruan@pa.msu.edu

Russell Zach Duke University, Durham, NC, USA  
zach.russell@duke.edu

Řiháček Tomáš Institute of Scientific Instruments, Brno, Czech Republic  
rihacek@isibrno.cz

Sasaki Tomoyo Hitachi High-Technologies, Ibaraki, Japan  
sasaki-tomoyo@naka.hitachi-hitec.com

Sed'a Bohuslav FEI Czech Republic, Brno, Czech Republic  
bohuslav.seda@fei.com

Schönhense Gerd Johannes Gutenberg University, Mainz, Germany  
gschoenhense@aol.com

Schwind Greg FEI Company, Hillsboro, OR, USA  
Greg.Schwind@FEI.com

Sise Omer Suleyman Demirel University, Cunur, Turkey  
omersise@gmail.com

Spivak-Lavrov Igor Aktobe Regional State University, Aktobe, Kazakhstan  
spivakif@rambler.ru

Srinivasan Avinash National University of Singapore, Singapore  
eleavsr@nus.edu.sg

Takeda Hiroyuki      RIKEN Nishina Center, Saitama, Japan  
351-0198takeda@ribf.riken.jp

Tesch Paul            Oregon Physics, Hillsboro, OR, USA  
p.tesch@oregon-physics.com

Thomas Sebastian     University Erlangen-Nürnberg, Erlangen  
Germany  
sebastian.thomas@fau.de

Tromp Rudolf         IBM T.J. Watson Research Center, Yorktown  
Heights, NY, USA  
rtromp@us.ibm.com

Trubitsyn Andrey     Ryazan State Radio Engineering University,  
Ryazan, Russia  
assur@bk.ru

Tuggle David         FEI Company, Hillsboro, OR, USA  
David.Tuggle@fei.com

Tusche Christian     Max-Planck-Institut für Mikrostrukturphysik,  
Halle, Germany  
tusche@mpi-halle.mpg.de

Uno Shinobu         JEOL Ltd., Tokyo, Japan  
suno@jeol.co.jp

Vašina Radovan      FEI Czech Republic, Brno, Czech Republic  
Radovan.Vasina@fei.com

Vering Guido         Raith GmbH, Dortmund, Germany  
vering@raith.de

Verruno Marina      CRP Gabriel Lippmann, Belvaux, Luxembourg  
verruno@lippmann.lu

Walker Andrew       Shimadzu Research Laboratory, Manchester,  
UK  
andrewr.walker@srlab.co.uk

Walker Christopher   Institute of Scientific Instruments, Brno,  
Czech Republic  
chris@isibrno.cz

Wang Xijie           SLAC National Accelerator Lab., Menlo Park,  
CA, USA  
wangxj@slac.stanford.edu

Winfield John        GSI Helmholtz Centre, Darmstadt, Germany  
j.winfield@gsi.de

Winkler Martin       GSI Helmholtz Centre, Darmstadt, Germany  
m.winkler@gsi.de

Wollnik Hermann     New Mexico State University, Las Cruces, NM,  
USA  
hwollnik@gmail.com

Yavor Mikhail        Institute for Analytical Instrumentation RAS,  
St. Petersburg, Russia  
mikhail.yavor@gmail.com

Zelinka Jiří          Institute of Scientific Instruments, Brno,  
Czech Republic  
zelinka@isibrno.cz

Zhang Yuhu           Institute of Modern Physics, Lanzhou, China  
yhzhang@impcas.ac.cn

Zlámál Jakub         Brno University of Technology, Brno,  
Czech Republic  
zlamal@fme.vutbr.cz

Zouros Theo          University of Crete, Heraklion, Crete, Greece  
tzouros@physics.uoc.gr

